

<b>Notice of References Cited</b>	Application/Control No. 10/708,825		Applicant(s)/Patent Under Reexamination BEENAU ET AL.	
	Examiner Daniel I. Walsh		Art Unit 2876	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,636,620	10-2003	Hoshino, Satoshi	382/124
*	B	US-5,942,761	08-1999	Tuli, Raja Singh	250/556
*	C	US-5,901,239	05-1999	Kamei, Toshio	382/125
*	D	US-2005/0005172	01-2005	Haala, Catherine A.	713/202
*	E	US-2002/0097142	07-2002	Janiak et al.	340/5.53
*	F	US-2003/0132297	07-2003	McCall et al.	235/472.01
*	G	US-2005/0122209	06-2005	Black, Gerald R.	340/005.52
*	H	US-2002/0043566	04-2002	Goodman et al.	235/492
*	I	US-6,257,486	07-2001	Teicher et al.	235/380
*	J	US-2005/0065872	03-2005	Moebs et al.	705/038
*	K	US-2002/0191816	12-2002	Maritzen et al.	382/115
*	L	US-6,925,565	08-2005	Black, Gerald R.	713/186
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.